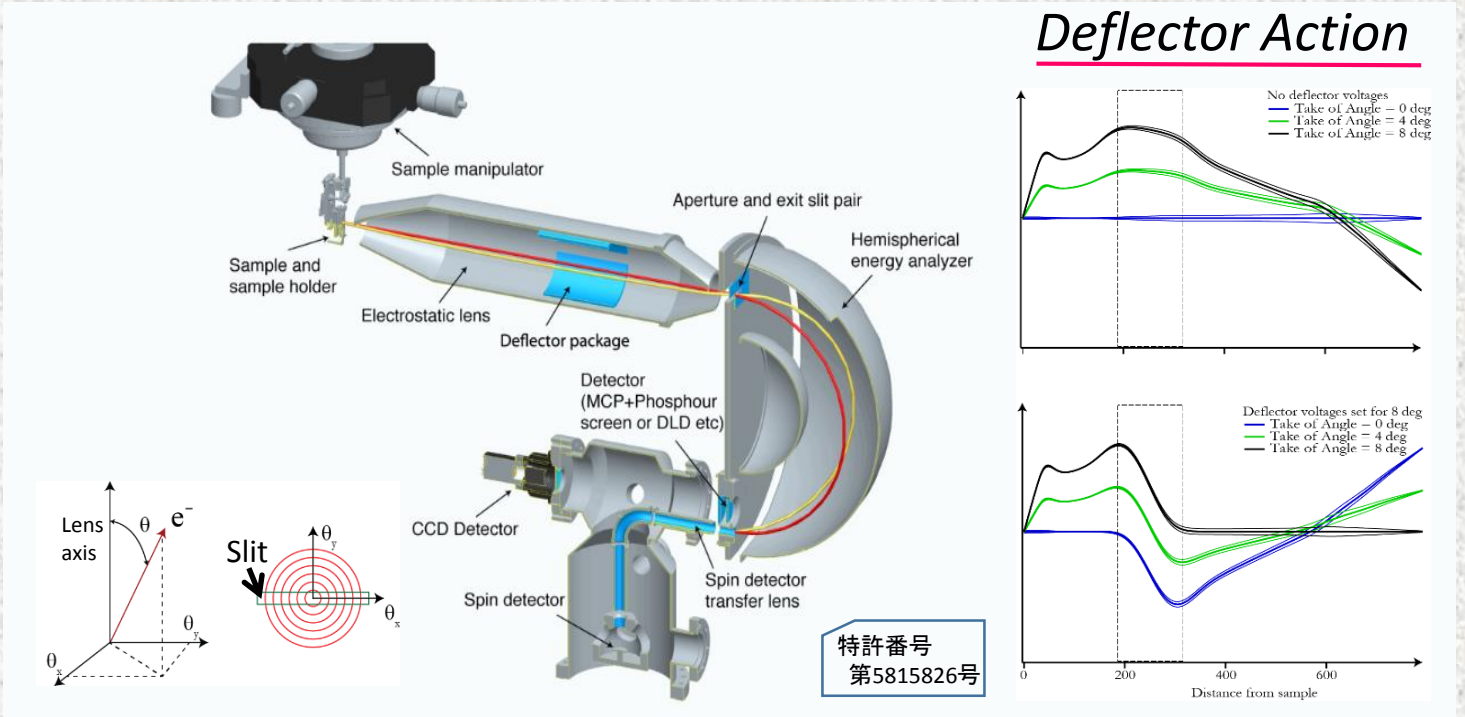
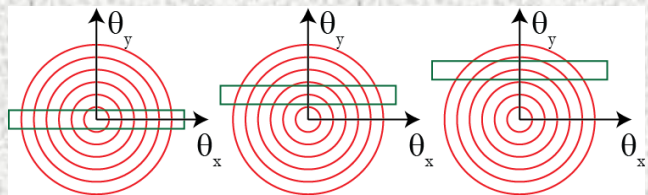


Deflector Analyser DA30

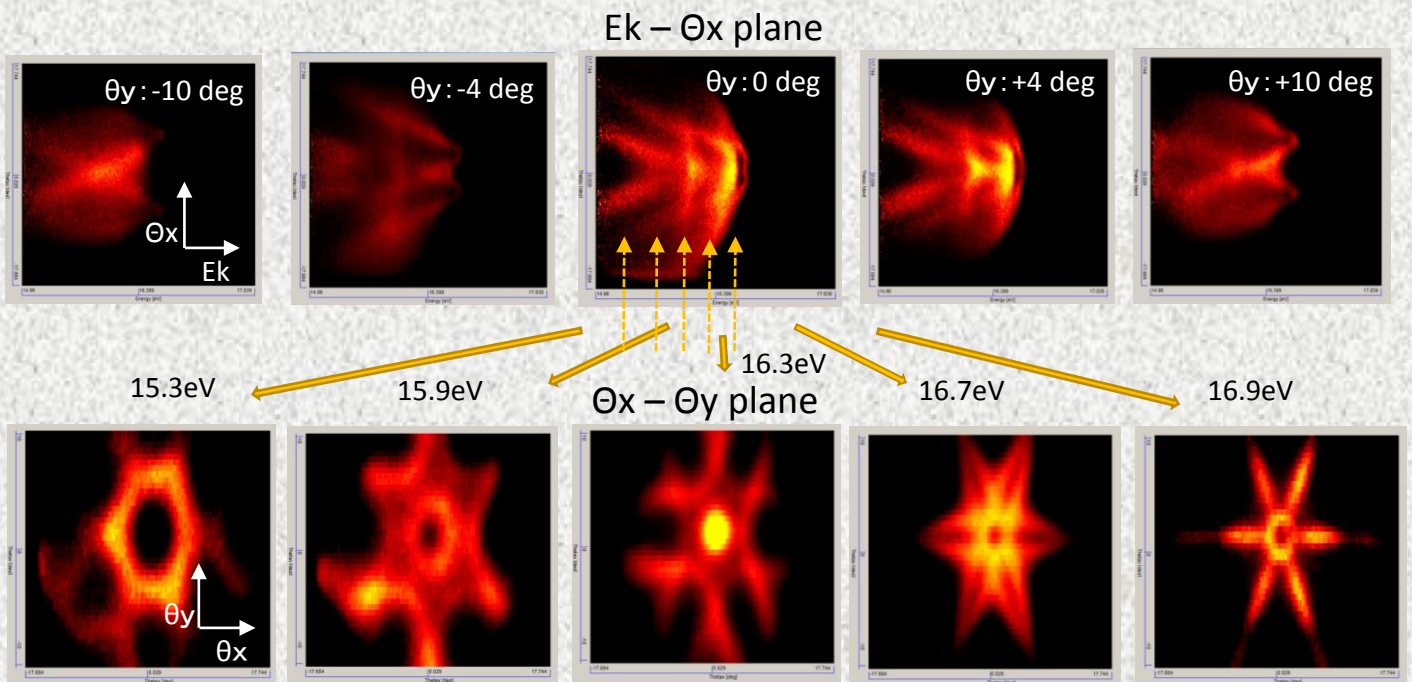
- With the deflector analyser, the electron trajectories can be deflected, to change the range of emission angles that reaches the detector
- Deflection can be done in θ_x ($\pm 15\text{deg}$) and in θ_y ($\pm 12\text{deg}$).



ARPES SCAN



Increasing deflection in θ_y



Bi on Si (Data courtesy: Dr.Yaji, ISSP)